

Reliability Report (Q2017-014)

PLA134 Product Reliability Test Single-Pole, Normally Open OptoMOS Relay

July 26, 2017

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<u>Summary</u>
The PLA134 product has successfully passed IXYS ICD's requirements for product reliability test.

Table 1: Device Information

Product Number	PLA134
Package Type	6 Pin DIP
Assembly Site	Atec, Laguna, Philippines
Test Site	IXYS ICD BEV, Beverly, MA, USA

Table 2: Reliability Test Result

Stress Test	Stress Conditions	Applicable Specs	Product/ Package	Sample Size (SS)	# of Failures
HTRB	125°C, 80% WVDC,	Mil-Std-883 M1005	PLA134 T71518	105	0
Thermal Shock	1000 hrs 0 to 100°C, 10/10 dwells,	JESD22-A-108 Mil-Std-883, M1011	PLA134 T71518	55	0
Temperature Cycle	15 cycles -55 to 125°C, 10/10 dwells, 300 cycles	Mil-Std-883, M1010, "B"	PLA134 T71518	55	0
Hot Storage	125C, 1000 hrs	JESD22-A103-C	PLA134 T71518	45	0
MSL	IR Reflow, Level 1	J-STD-020D.1	PLA134 T71518	25	0

Table 3: FIT Rate Summary

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Qual	Stress	# of	# of	Hours	Equivalent	FIT Rate
Lot #	Test	Devices	Fail	Tested	Dev. Hours	@ 60% CL
1	HTRB	105	0	1000	26,817,626	34.31*

^{*} HTRB FIT Rate was calculated based on the Acceleration Factor (AF) and equivalent device hours at 0.7eV of activation energy at 125°C test temperature and 40°C use temperature.

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Approvals

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